

L Number	Hits	Search Text	DB	Time stamp
-	2547	250/310	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:47
-	3406	250/311	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:47
-	4711	250/492.2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:48
-	2270	250/307	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:48
-	312	250/440.11	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:48
-	0	(Transmission near2 electron near2 (microscope or microscopy) or TEM) and (Beam or probe or arm or (micro near2 hand) or tip or needle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 09:58
-	1079868	@pd>20030801	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11
-	10531	250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:07
-	76215	(Beam or probe or arm or (micro near2 hand) or tip or needle) and (((scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:07
-	8551	((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:10
-	6740	((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:31
-	2395797	@pd>20021219	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11

	334349	@ad>20021219	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11
	14670	@ad>20030801	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11
	2395911	@pd>20021219 or @ad>20021219	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11
	1079969	@pd>20030801 or @ad>20030801	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:11
	605	(@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:12
	337	((@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)) and ((Beam or probe or arm or (micro near2 hand) or tip or needle) and (((scanning adj electron adj microscope) or (scanning near3 microscope) or SEM) or (ion adj beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:12
	54) ((@pd>20030801 or @ad>20030801) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:12
	107	(@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))) (Beam or probe or arm or (micro near2 hand) or tip or needle) SAME (rotat\$5 or circ\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:13
	888660	(Beam or probe or arm or (micro near2 hand) or tip or needle) SAME (rotat\$5 or circ\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:22
	60	((Beam or probe or arm or (micro near2 hand) or tip or needle) SAME (rotat\$5 or circ\$5)) and ((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11)) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) and (Beam or probe or arm or (micro near2 hand) or tip or needle)) and (sample or workpiece or specimen))) (Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or circ\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:18
	625608	(Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or circ\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:21

	587309	(Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:22
	23124	((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:31
	342	(@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 11:31
	30) ((Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot)) and (((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 12:03
	95) ((@pd>20021219 or @ad>20021219) and (250/310 or 250/311 or 250/492.2 or 250/307 or 250/440.11) and (((Transmission near2 electron near2 (microscope or microscopy or TEM)) or SEM or (scanning adj electron adj microscope)) and (Beam or probe or arm or (micro near2 hand) or tip or needle) and (sample or workpiece or specimen)))) and ((Beam or probe or arm or (micro near2 hand) or tip or needle) WITH (rotat\$5 or Circle or circular or pivot))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/16 12:03